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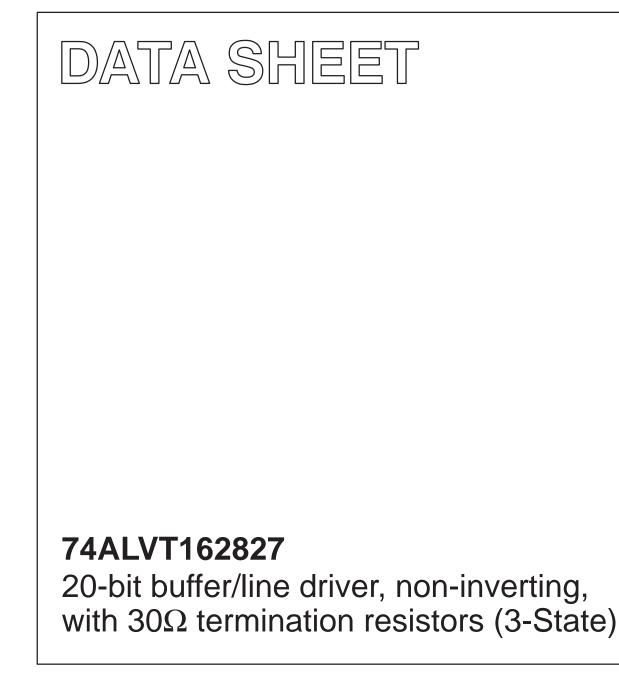
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Kind regards,

Team Nexperia

INTEGRATED CIRCUITS



Product specification Supersedes data of 1997 May 01 IC23 Data Handbook 1998 Feb 13



Philips Semiconductors

74ALVT162827

FEATURES

- Multiple V_{CC} and GND pins minimize switching noise
- 5V I/O Compatible
- Live insertion/extraction permitted
- 3-State output buffers
- Outputs include series resistance of 30Ω making external termination resistors unnecessary
- Power-up 3-State
- Output capability: +12mA/–12mA
- Latch-up protection exceeds 500mA per Jedec Std 17
- ESD protection exceeds 2000 V per MIL STD 883 Method 3015 and 200 V per Machine Model
- Bus hold data inputs eliminate the need for external pull-up resistors to hold unused inputs

QUICK REFERENCE DATA

DESCRIPTION

The 74ALVT162827 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive. It is designed for V_{CC} operation at 2.5V or 3.3V with I/O compatibility to 5V.

The 74ALVT162827 20-bit buffers provide high performance bus interface buffering for wide data/address paths or buses carrying parity. They have NOR Output Enables (n $\overline{OE1}$, n $\overline{OE2}$) for maximum control flexibility.

The 74ALVT162827 is designed with 30Ω series resistance in both the pull-up and pull-down output structures. This design reduces line noise in applications such as memory address drivers, clock drivers and bus receivers/transmitters.

SYMBOL	PARAMETER	CONDITIONS	TYPI	UNIT	
STMBOL	FARAMETER	T _{amb} = 25°C	2.5V	3.3V	UNIT
t _{PLH} t _{PHL}	Propagation delay nAx to nBx or nBx to nAx	C _L = 50pF	2.7 2.3	2.2 2.0	ns
C _{IN}	Input capacitance DIR, OE	$V_I = 0V \text{ or } V_{CC}$	3	3	pF
C _{Out}	Output capacitance	$V_{I/O} = 0V \text{ or } V_{CC}$	9	9	pF
I _{CCZ}	Total supply current	Outputs disabled	40	70	μA

ORDERING INFORMATION

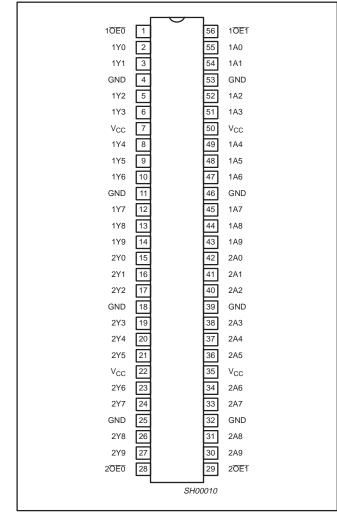
PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
56-Pin Plastic SSOP Type III	–40°C to +85°C	74ALVT162827 DL	AV162827 DL	SOT371-1
56-Pin Plastic TSSOP Type II	–40°C to +85°C	74ALVT162827 DGG	AV162827 DGG	SOT364-1

PIN DESCRIPTION

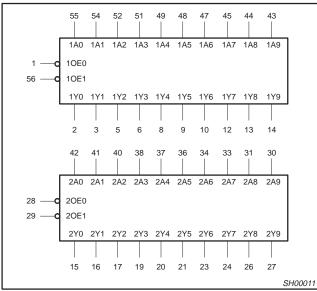
PIN NUMBER	SYMBOL	FUNCTION		
55, 54, 52, 51, 49, 48, 47, 45, 44, 43, 42, 41, 40, 38, 37, 36, 34, 33, 31, 30	1A0 - 1A9 2A0 - 2A9	Data inputs		
2, 3, 5, 6, 8, 9, 10, 12, 13, 14, 15, 16, 17, 19, 20, 21, 23, 24, 26, 27	1Y0 - 1Y9 2Y0 - 2Y9	Data outputs		
1, 56, 28, 29	10E0, 10E1 20E0, 20E1	Output enable inputs (active-Low)		
4, 11, 18, 25, 32, 39, 46, 53	GND	Ground (0V)		
7, 22, 35, 50	V _{CC}	Positive supply voltage		

74ALVT162827

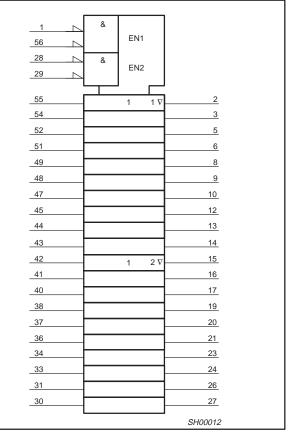
PIN CONFIGURATION



LOGIC SYMBOL



LOGIC SYMBOL (IEEE/IEC)



FUNCTION TABLE

INPU	JTS	OUTPUTS	OPERATING MODE
nOEx	nAx	nYx	
L	L	L	Transparent
L	Н	Н	Transparent
Н	Х	Z	High impedance

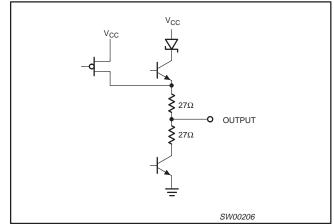
X = Don't careZ = High imped

= High impedance "off" state

H = High voltage level

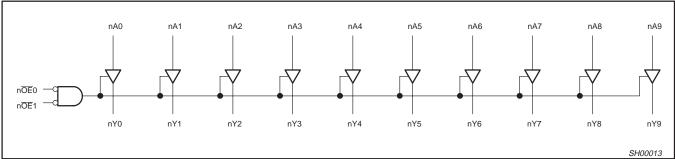
L = Low voltage level

SCHEMATIC OF EACH OUTPUT



74ALVT162827

LOGIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS^{1, 2}

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +7.0	V
I _{IK}	DC input diode current	V ₁ < 0	-18	mA
VI	DC input voltage ³		-1.2 to +7.0	V
I _{ОК}	DC output diode current	V _O < 0	-50	mA
V _{OUT}	DC output voltage ³	output in Off or High state	-0.5 to +5.5	V
I _{OUT}	DC output current	output in Low state	128	mA
T _{stg}	Storage temperature range		-65 to 150	°C

NOTES:

 Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

 The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.

3. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	2.5V RANGE LIMITS		3.3V RANGE LIMITS		UNIT	
		MIN	MAX	MIN	MAX	UNIT	
V _{CC}	DC supply voltage	2.3	2.7	3.0	3.6	V	
VI	Input voltage	0	5.5	0	5.5	V	
V _{IH}	High-level input voltage	1.7		2.0		V	
V _{IL}	Input voltage		0.7		0.8	V	
I _{ОН}	High-level output current		-8		-12	mA	
I _{OL}	Low-level output current		12		12	mA	
Δt/Δv	Input transition rise or fall rate; Outputs enabled		10		10	ns/V	
T _{amb}	Operating free-air temperature range	-40	+85	-40	+85	°C	

74ALVT162827

DC ELECTRICAL CHARACTERISTICS (3.3V ± 0.3V RANGE)

					LIMITS		
SYMBOL	PARAMETER	TEST CONDITIONS		Temp = -40°C to +85°		+85°C	
				MIN	TYP ¹	MAX	1
V _{IK}	Input clamp voltage	$V_{CC} = 3.0V; I_{IK} = -18mA$			-0.85	-1.2	V
V _{OH}	High-level output voltage	$V_{CC} = 3.0V; I_{OH} = -12mA$		2.0	2.3		V
V _{OL}	Low-level output voltage	V _{CC} = 3.0V; I _{OL} = 12mA			0.5	0.8	V
		$V_{CC} = 3.6V; V_I = V_{CC} \text{ or } GND$	Control pins		0.1	±1	
		$V_{CC} = 0 \text{ or } 3.6 \text{V}; \text{ V}_{I} = 5.5 \text{V}$			0.1	10	
łı	Input leakage current	$V_{CC} = 3.6V; V_1 = V_{CC}$	Deterring		0.5	1	μA
		$V_{CC} = 3.6V; V_{I} = 0$	Data pins ⁴		0.1	-5	
I _{OFF}	Off current	$V_{CC} = 0V$; V_{I} or $V_{O} = 0$ to 4.5V	•		0.1	±100	μA
	Bus Hold current $V_{CC} = 3V; V_1 = 0.8V$ Data inputs ⁶ $V_{CC} = 3V; V_1 = 2.0V$			75	130		μA
I _{HOLD}				-75	-140		μA
	Data inputs	$V_{CC} = 0V$ to 3.6V; $V_{CC} = 3.6V$		±500			μA
I_{EX}	Current into an output in the High state when $V_O > V_{CC}$	$V_{O} = 5.5V; V_{CC} = 3.0V$			10	125	μΑ
I _{PU/PD}	Power up/down 3-State output current ³	$V_{CC} \leq$ 1.2V; V_{O} = 0.5V to $V_{CC};$ V_{I} = GNI OE/OE = Don't care	D or V _{CC}		1	±100	μA
I _{OZH}	3-State output High current	V_{CC} = 3.6V; V_{O} = 3.0V; V_{I} = V_{IL} or V_{IH}			0.5	5	μA
I _{OZL}	3-State output Low current	V_{CC} = 3.6V; V_{O} = 0.5V; V_{I} = V_{IL} or V_{IH}			0.5	-5	μA
I _{CCH}		V_{CC} = 3.6V; Outputs High, V_{I} = GND or	V _{CC} , I _{O =} 0		0.07	0.1	
I _{CCL}	Quiescent supply current	V_{CC} = 3.6V; Outputs Low, V_I = GND or V_{CC} , I_O = 0			3.9	5.5	mA
I _{CCZ}]	$V_{CC} = 3.6V$; Outputs Disabled; $V_I = GNI$	D or V _{CC} , $I_O = 0^5$		0.07	0.1	
ΔI_{CC}	Additional supply current per input pin ²	V_{CC} = 3V to 3.6V; One input at V _{CC} -0.6 Other inputs at V _{CC} or GND	iV,		0.04	0.4	mA

NOTES:

1. All typical values are at $V_{CC} = 3.3V$ and $T_{amb} = 25^{\circ}C$. 2. This is the increase in supply current for each input at the specified voltage level other than V_{CC} or GND 3. This parameter is valid for any V_{CC} between 0V and 1.2V with a transition time of up to 10msec. From $V_{CC} = 1.2V$ to $V_{CC} = 3.3V \pm 0.3V$ a transition time of 100µsec is permitted. This parameter is valid for $T_{amb} = 25^{\circ}C$ only.

4. Unused pins at V_{CC} or GND. 5. I_{CCZ} is measured with outputs pulled up to V_{CC} or pulled down to ground.

6. This is the bus hold overdrive current required to force the input to the opposite logic state.

AC CHARACTERISTICS (3.3V ± 0.3V RANGE)

GND = 0V, $t_R = t_F = 2.5$ ns, $C_L = 50$ pF, $R_L = 500\Omega$

				LIMITS		
SYMBOL	PARAMETER	WAVEFORM	T _{ar} V(_{nb} = -40 to +8 _{CC} = +3.3V ±0.	5°C 3V	UNIT
			MIN	TYP	MAX	
t _{PLH} t _{PHL}	Propagation delay nAx to nYx	1	1.0 1.0	2.2 2.0	3.3 3.0	ns
t _{PZH} t _{PZL}	Output enable time to High and Low level	2	1.5 1.0	3.4 2.4	5.6 3.7	ns
t _{PHZ} t _{PLZ}	Output disable time from High and Low level	2	1.5 1.0	3.4 2.7	5.2 4.5	ns

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DC ELECTRICAL CHARACTERISTICS (2.5V ± 0.2V RANGE)

		TEST CONDITIONS			LIMITS		
SYMBOL	PARAMETER			Temp =	+85°C	UNIT	
				MIN	TYP ¹	MAX	
VIK	Input clamp voltage	V _{CC} = 2.3V; I _{IK} = -18mA			-0.85	-1.2	V
V _{OH}	High-level output voltage	V _{CC} = 2.3V; I _{OH} = -8mA		1.7	2.3		V
V _{OL}	Low-level output voltage	V _{CC} = 2.3V; I _{OL} = 12mA			0.5	0.7	V
		$V_{CC} = 2.7V$; $V_I = V_{CC}$ or GND	Control pins		0.1	±1	
1.	Input leakage current	$V_{CC} = 0 \text{ or } 2.7 \text{V}; \text{ V}_{\text{I}} = 5.5 \text{V}$			0.1	10	μA
łı	input leakage current	$V_{CC} = 2.7V; V_{I} = V_{CC}$	Data pins4		0.1	1	μΑ
		$V_{CC} = 2.7V; V_I = 0$	Data pins		0.1	-5	1
I _{OFF}	Off current	$V_{CC} = 0V; V_{I} \text{ or } V_{O} = 0 \text{ to } 4.5V$	$V_{CC} = 0V; V_{I} \text{ or } V_{O} = 0 \text{ to } 4.5V$		0.1	±100	μΑ
I _{HOLD}	Bus Hold current	$V_{CC} = 2.3V; V_{I} = 0.7V$	V _{CC} = 2.3V; V _I = 0.7V		115		
HOLD	Data inputs ⁶	V _{CC} = 2.3V; V _I = 1.7V			-10		μA
I_{EX}	Current into an output in the High state when $V_O > V_{CC}$	V _O = 5.5V; V _{CC} = 2.3V			10	125	μA
I _{PU/PD}	Power up/down 3-State output current ³	$V_{CC} \le 1.2$ V; $V_O = 0.5$ V to V_{CC} ; $V_I = GNE OE/OE = Don't care$) or V _{CC} ;		1	100	μA
I _{OZH}	3-State output High current	V_{CC} = 2.7V; V_{O} = 2.3V; V_{I} = V_{IL} or V_{IH}			0.5	5	μΑ
I _{OZL}	3-State output Low current	V_{CC} = 2.7V; V_O = 0.5V; V_I = V_{IL} or V_{IH}			0.5	-5	μΑ
I _{CCH}		V_{CC} = 2.7V; Outputs High, V_I = GND or	$V_{CC} = 2.7V$; Outputs High, $V_I = GND$ or V_{CC} , $I_O = 0$		0.04	0.1	
I _{CCL}	Quiescent supply current	V_{CC} = 2.7V; Outputs Low, V_I = GND or V_{CC} , I_O = 0			3.5	5.0	mA
I _{CCZ}	1	V_{CC} = 2.7V; Outputs Disabled; V_I = GND or V_{CC} , $I_O = 0^5$			0.04	0.1	
ΔI_{CC}	Additional supply current per input pin ²	V_{CC} = 2.3V to 2.7V; One input at V_{CC} -0 Other inputs at V_{CC} or GND	.6V,		0.04	0.4	mA

NOTES:

1. All typical values are at $V_{CC} = 2.5V$ and $T_{amb} = 25^{\circ}C$. 2. This is the increase in supply current for each input at the specified voltage level other than V_{CC} or GND

3. This parameter is valid for any V_{CC} between 0V and 1.2V with a transition time of up to 10msec. From V_{CC} = 1.2V to V_{CC} = 2.5V \pm 0.2V a transition time of 100µsec is permitted. This parameter is valid for T_{amb} = 25°C only.

4. Unused pins at V_{CC} or GND.

5. I_{CCZ} is measured with outputs pulled up to V_{CC} or pulled down to ground.

6. Not guaranteed.

AC CHARACTERISTICS (2.5V \pm 0.2V RANGE)

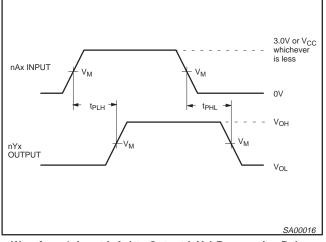
GND = 0V, $t_R = t_F = 2.5$ ns, $C_L = 50$ pF, $R_L = 500\Omega$

				LIMITS		
SYMBOL	PARAMETER	WAVEFORM	T _{ar} V(_{nb} = -40 to +8 _{CC} = +2.5V ±0.	5°C 2V	UNIT
			MIN	TYP	MAX	
t _{PLH} t _{PHL}	Propagation delay nAx to nYx	1	1.5 1.5	2.7 2.3	4.5 3.5	ns
t _{PZH} t _{PZL}	Output enable time to High and Low level	2	2.5 1.5	4.7 2.9	7.5 4.7	ns
t _{PHZ} t _{PLZ}	Output disable time from High and Low level	2	1.5 1.0	3.2 2.4	5.2 4.0	ns

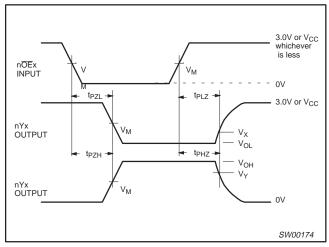
74ALVT162827

AC WAVEFORMS

 $\begin{array}{l} {\sf V}_{M} = 1.5 {\sf V} \mbox{ for } {\sf V}_{CC} \geq 3.0 {\sf V}; \mbox{ } {\sf V}_{M} = {\sf V}_{CC}/2 \mbox{ for } {\sf V}_{CC} \leq 2.7 {\sf V} \\ {\sf V}_{X} = {\sf V}_{OL} + 0.3 {\sf V} \mbox{ for } {\sf V}_{CC} \geq 3.0 {\sf V}; \mbox{ } {\sf V}_{X} = {\sf V}_{OL} + 0.15 {\sf V} \mbox{ for } {\sf V}_{CC} \leq 2.7 {\sf V} \\ {\sf V}_{Y} = {\sf V}_{OH} - 0.3 {\sf V} \mbox{ for } {\sf V}_{CC} \geq 3.0 {\sf V}; \mbox{ } {\sf V}_{Y} = {\sf V}_{OH} - 0.15 {\sf V} \mbox{ for } {\sf V}_{CC} \leq 2.7 {\sf V} \\ \end{array}$

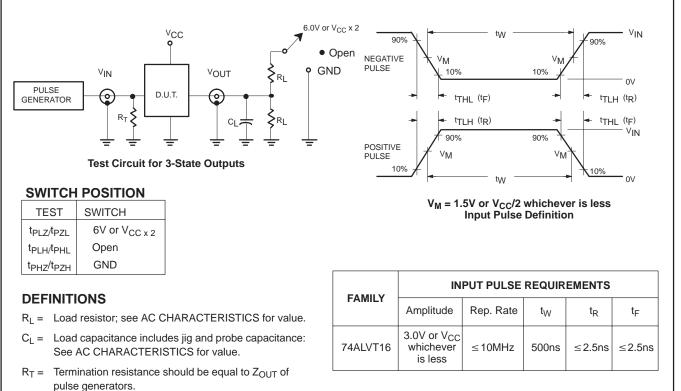






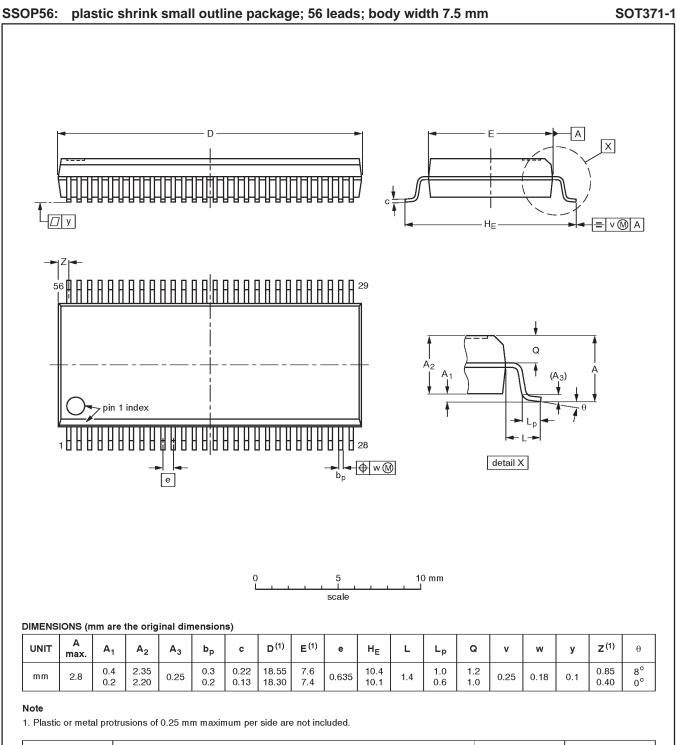
Waveform 2. 3-State Output Enable and Disable Times

TEST CIRCUIT AND WAVEFORM



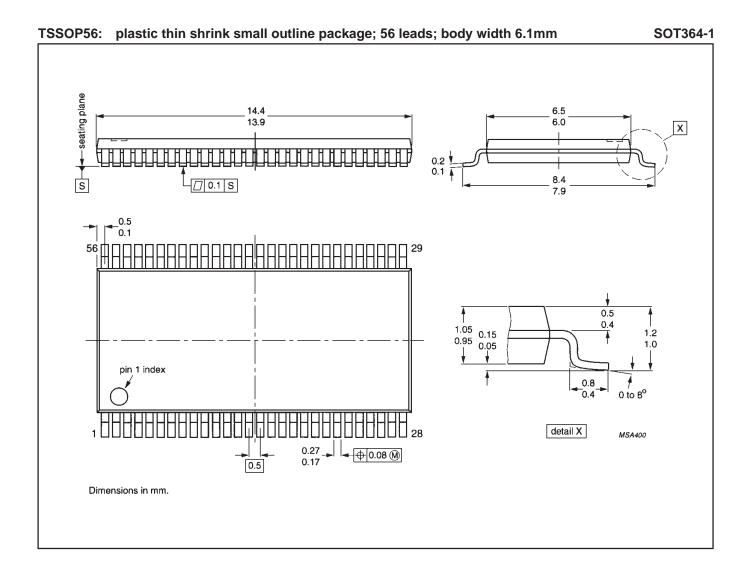
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74ALVT162827



OUTLINE		REFERENCES				ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT371-1		MO-118AB				-93-11-02 95-02-04

74ALVT162827



Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
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